JOURNAL OF QUALITY TECHNOLOGY

Index

Volume 38, Nos. 1–4, 2006

ARTICLES

All articles are listed alphabetically by author and numbered sequentially. These sequential article numbers are used to identify the articles in the Key Words list, which begins on page 383.

1. Benneyan, J. C., *Discussion* . . . . . April, 113–123
2. Burkom, H., *Discussion* . . . . . April, 127–132
3. Chen, W; Jin, R.; and Sudjianto, A., *Analytical Global Sensitivity Analysis and Uncertainty Propagation for Robust Design* . . . . . October, 333–348
4. Ding, Y.; Zeng, L.; and Zhou, S., *Phase I Analysis for Monitoring Nonlinear Profiles in Manufacturing Processes* . . . . . July, 199–216
5. Giorgio, M.; Guida, M.; and Pulcini, G., *Reliability-Growth Analysis of Locomotive Electrical Equipment* . . . . . January, 014–030
6. Goos, P. and Donev, A., *The D-Optimal Design of Blocked Experiments with Mixture Components* . . . . . October, 319–332
7. Goos, P.; Langhans, I.; and Vanderbroek, M., *Practical Inference from Industrial Split-Plot Designs* . . . . . April, 162–179
8. Grigg, O. A. and Spiegelhalter, D. J., *Discussion* . . . . . April, 124–126
9. Gutiérrez-Pulido, H.; Aguirre-Torres, V.; and Christen, J. A., *A Bayesian Approach for the Determination of Warranty Length* . . . . . April, 180–189
10. Jensen, W. A.; Jones-Farmer, L. A.; Champ, C. W.; and Woodall, W. H., *Effects of Parameter Estimation on Control Chart Properties: A Literature Review* . . October, 349–364
11. Kerr, K. F., *Efficient 2^k Factorial Designs for Blocks of Size 2 with Microarray Applications* . . . . . October, 309–318
12. Kulahci, M.; Ramírez, J. G.; and Tobias, R., *Split-Plot Fractional Designs: Is Minimum Aberration Enough?* . . . . . January, 056–064
13. Leemis, L. M., *Lower System Reliability Bounds from Binary Failure Data Using Bootstrapping* . . . . . January, 002–013
14. Lu, X.; Li, W.; and Xie, M., *A Class of Nearly Orthogonal Arrays* . . . . . April, 148–161
15. Lucas, J. M. and Watkins, R., *Discussion* . . . . . April, 108–110
16. McLeod, R. G. and Brewster, J. F., *Blocked Fractional Factorial Split-Plot Experiments for Robust Parameter Design* . . . . . July, 267–279
17. Mohammed, M. A., *Discussion* . . . . . April, 105–107
18. Polansky, A. M., *Permutation Methods for Comparing Process Capabilities* . . . . . July, 254–266
19. Reynolds, Jr., M. R. and Cho, G.-Y., *Multivariate Control Charts for Monitoring the Mean Vector and Covariance Matrix* . . . . . July, 230–253
20. Robinson, T. J.; Wulff, S. S.; Montgomery, D. C.; and Khuri, A. I., *Robust Parameter Design Using Generalized Linear Mixed Models* . . . . . January, 065–075
21. Sexton, C. J.; Anthony, D. K.; Lewis, S. M.; Please, C. P.; and Keane, A. J., *Design of Experiment Algorithms for Assembled Products* . . . . . October, 298–308
22. Shu, L. and Jiang, W., *A Markov Chain Model for the Adaptive CUSUM Control Chart* . . . . . April, 135–147
23. Steiner, S. H., *Discussion* . . . . . April, 111–112
24. Tang, L.-C. and Cheong, W.-T., *A Control Scheme for High-Yield Correlated Production Under Group Inspection* . . . . . January, 045–055

25. TSUNG, F.; ZHAO, Y.; XIANG, L.; AND JIANG, W., *Improved Design of Proportional Integral Derivative Charts* . . . . . January, 031–044
26. VAN DER MERWE, A. J.; PRETORIUS, A. L.; AND MEYER, J. H., *Bayesian Tolerance Intervals for the Unbalanced One-Way Random Effects Model* . . . . . July, 280–293
27. WILLIAMS, J. D.; WOODALL, W. H.; BIRCH, J. B.; AND SULLIVAN, J. H., *Distribution of Hotelling's T^2 Statistic Based on the Successive Differences Estimator* . . . . . July, 217–229
28. WOODALL, W. H., *The Use of Control Charts in Health-Care and Public-Health Surveillance* . . . . . April, 089–104
29. WOODALL, W. H., *Rejoinder* . . . . . April, 133–134
30. ZANTEK, P. F., *Design of Cumulative Sum Schemes for Start-Up Processes and Short Runs* . . . . . October, 365–375

DEPARTMENTS

Book Reviews

The Analysis of Means: A Graphical Method for Comparing Means, Rates, and Proportions by P. R. Nelson, P. S. Wludyka, and K. A. F. Copeland . . . . . T. P. RYAN April, 191–193
Design and Analysis of Experiments, Vol. 2 by K. Hinkelmann and O. Kempthorne . . . . . T. P. RYAN January, 080–082
Design and An alysis of Games R&R Studies: Making Decisions with Confidence Intervals in Random Mixed ANOVA Models by R. K. Burdick, C. M. Borror, and D. C. Montgomery by . . . . . J. G. VOELKEL April, 193–195
Introduction to Nonparametric Regression by K. Takezawa . . . . . D. NYCHKA April, 190–191
Introduction to Regression Modeling by B. Abraham and J. Ledolter . . . . . J. B. GRAY October, 367–377
Mastering Statistical Process Control: A Handbook for Performance Improvement Using Cases by T. Stapenhurst . . . . . T. P. RYAN July, 294–296
Process Quality Control: Troubleshooting and Interpretation of Data, Fourth Edition by E. R. Ott, E. G. Schilling, and D. V. Neubauer . . . . . N. DOGANAKSOY January, 076–078
Quality by Experimental Design, Third Edition by T. B. Barker . . . . . R. G. MCLEOD October, 377–379
SPC for Right-Brain Thinkers: Process Control for Non-Statisticians by L. Roberts . . . . . W. H. WOODALL October, 379-380
Statistics for Experimenters: Design, Innovation, and Discovery, Second Edition by G. E. P. Box, J. S. Hunter, and W. G. Hunter . . . . . D. K. J. LIN January, 078–080

Book Reviewers

Doganaksoy, N. . . . . January, 076–078
Gray, J. B. . . . . October, 376–377
Lin, D. K. J. . . . . January, 078–080
McLeod, R. G. . . . . October, 377–379
Nychka, D. . . . . April, 190–191
Ryan, T. P. . . . . January, 080–082
Ryan, T. P. . . . . April, 191–193
Ryan, T. P. . . . . July, 294–296
Voelkel, J. G. . . . . April, 193–195
Woodall, W. H. . . . . October, 379–380

MISCELLANEOUS

Announcement from the Editor . . . . . January, 001
Corrigendum . . . . . January, 083
Corrigendum . . . . . April, 196
Corrigendum . . . . . April, 197
Editorial . . . . . October, 297

Editorial Collaborators . . . . . October, 385
Letter to the Editor . . . . . April, 086

KEY WORDS

The numbers listed by the key words are the identification numbers assigned to the articles as listed on the previous pages.

Analytical Formulation; 3
Approximate Distribution; 27
ARL; 10
Average Run Length; 22, 25
Bayesian Procedure; 26
Beta Distribution; 13
Binomial Confidence Interval; 13
Block Design; 11
Blocked Factorial; 11
Blocking; 16
Bonferroni; 18
Bootstrap; 18
Change-Point Detection; 4
Cluster Detection; 28
Clustering; 4
Coherent System; 13
Computer Algebra System; 13
Conditional Distribution; 10
Containment Method; 7
Control Charts; 4, 25
Control Factors; 16
Correlation Within Sample; 24
Cumulative Conformance Count; 24
Cumulative Sum Chart; 28
CUSUM; 28
D-Optimalty; 21
Design Criterion; 12
Dissatisfaction Cost Function; 9
Economic Benefit Function; 9
Exchange Algorithm; 21
Expected Utility Function; 9
EWMA; 22, 28
Factorial Design; 11
False Alarm Rate; 27
Fixed and Random Blocks; 6
Fractional Factorial; 11
Generalized Least Squares; 7
Genetic Algorithm; 21
Global Sensitivity Analysis; 3
High-Volume Production; 24
Locomotive Electrical Equipment; 5
Marginal Distribution; 10
Mean-Shift Pattern; 25
Metamodeling; 3
Method of Kenward and Roger; 7
Minimum-Support Design; 6
Mixed Poisson Reliability-Growrh Model; 5
Mixture Experiment; 6
Monte Carlo Simulation; 26
Multiple Comparisons; 18
Multivariate Analysis; 4
Multivariate Exponentially Weighted Moving Average Control Chart; 19
Multivariate SPC; 27
Nearly Orthogonal Array of Strength m; 14
Noise Factors; 16
Noise Variables; 20
Nonnormal; 20
Optimal Designs; 16
Ordinary Least Squares; 7
Orthogonal Array; 14
Orthogonal Blocking; 6
p-Value; 18
Phase I; 10
Phase II; 10
Predicative Density; 26
Posterior Predictive Reliability; 9
Predictive Density; 26
Prior Warranty Information; 9
Process Variables; 6
Probability Matching Prior; 26
Proportional Integral Derivative; 25
Q Chart; 30
Qualitative Variables; 6
Random Effects; 20, 26
Randomization; 18
Reference Prior; 26
Regression Adjustment of Variables; 19
Reliability Demonstration Test; 5
Residual Method; 7
Response Surface Methodology; 20
Response Surface Modeling; 3
Restricted Randomization; 16
Restriction on Randomization; 12
Risk-Adjustment; 28
Robust Design; 3, 12, 20
Run-Length Distribution; 30
Run-Length Performance; 10

Sample Size; 10, 27
Sampling Inspection; 24
Satterthwaite's Method; 7
Search; 21
Self-Starting Method; 30
Sequential Probability Ratio Test; 28
Sequential Processes; 12
Sets Method; 28
Shewhart Chart; 10, 19
SPC; 28
Squared Deviation from Target; 19
Statistical Process Control; 10, 19, 22, 28, 30
Steady-State Average Time to Signal; 19
Strength; 14
T^2 Control Chart; 27
Tensor Basis Product Function; 3
Tolerance Intervals; 26
Uncertainty Propagation; 3
Warranty Cost Function; 9